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May 2014

FDMS7700S

Dual N-Channel PowerTrench® MOSFET

N-Channel: 30 V, 30 A, 7.5 m Ω N-Channel: 30 V, 40 A, 2.4 m Ω

Features

Q1: N-Channel

- Max $r_{DS(on)}$ = 7.5 m Ω at V_{GS} = 10 V, I_D = 12 A
- Max $r_{DS(on)}$ = 12 m Ω at V_{GS} = 4.5 V, I_D = 10 A

Q2: N-Channel

- Max $r_{DS(on)}$ = 2.4 m Ω at V_{GS} = 10 V, I_D = 20 A
- Max $r_{DS(on)} = 2.9 \text{ m}\Omega$ at $V_{GS} = 4.5 \text{ V}$, $I_D = 18 \text{ A}$
- RoHS Compliant

General Description

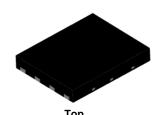
This device includes two specialized N-Channel MOSFETs in a dual MLP package. The switch node has been internally connected to enable easy placement and routing of synchronous buck converters. The control MOSFET (Q1) and synchronous SyncFETTM (Q2) have been designed to provide optimal power efficiency.

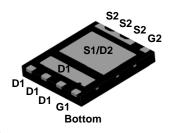
Applications

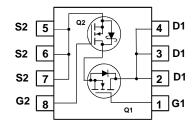
- Computing
- Communications
- General Purpose Point of Load



■ Notebook VCORE







Power 56

MOSFET Maximum Ratings T_A = 25 °C unless otherwise noted

Symbol	Parameter		Q1	Q2	Units
V _{DS}	Drain to Source Voltage		30	30	V
V_{GS}	Gate to Source Voltage	(Note 3)	±20	±20	V
I _D	Drain Current -Continuous	T _C = 25 °C	30	40	
	-Continuous	T _A = 25 °C	12 ^{1a}	22 ^{1b}	А
	-Pulsed		40	60	
P _D	Power Dissipation for Single Operation	T _A = 25 °C	2.2 ^{1a}	2.5 ^{1b}	W
		T _A = 25 °C	1.0 ^{1c}	1.0 ^{1d}	VV
T _J , T _{STG}	Operating and Storage Junction Temperature Range		-55 to	+150	°C

Thermal Characteristics

$R_{\theta JA}$	Thermal Resistance, Junction to Ambient	57 ^{1a}	50 ^{1b}	
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient	125 ^{1c}	120 ^{1d}	°C/W
$R_{\theta JC}$	Thermal Resistance, Junction to Case	3.5	2	

Package Marking and Ordering Information

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDMS7700S	FDMS7700S	Power 56	13 "	12 mm	3000 units

Electrical Characteristics $T_J = 25$ °C unless otherwise noted

Parameter	Test Conditions	Type	Min	Тур	Max	Units
cteristics						
Drain to Source Breakdown Voltage	$I_D = 250 \mu A, V_{GS} = 0 V$ $I_D = 1 mA, V_{GS} = 0 V$	Q1 Q2	30 30			V
Breakdown Voltage Temperature Coefficient	I_D = 250 μ A, referenced to 25 °C I_D = 1 mA, referenced to 25 °C	Q1 Q2		15 14		mV/°C
Zero Gate Voltage Drain Current	V _{DS} = 24 V, V _{GS} = 0 V	Q1 Q2			1 500	μ Α μ Α
Gate to Source Leakage Current	V _{GS} = 20 V, V _{DS} = 0 V	Q1 Q2			100 100	nA nA
	Cteristics Drain to Source Breakdown Voltage Breakdown Voltage Temperature Coefficient Zero Gate Voltage Drain Current		Cteristics Drain to Source Breakdown Voltage $I_D = 250 \mu\text{A}, V_{GS} = 0 \text{V}$ Q2 Breakdown Voltage Temperature $I_D = 250 \mu\text{A}, \text{V}_{GS} = 0 \text{V}$ Q2 Coefficient $I_D = 250 \mu\text{A}, \text{referenced to } 25 ^{\circ}\text{C}$ Q1 Coefficient $I_D = 1 \text{mA}, \text{referenced to } 25 ^{\circ}\text{C}$ Q2 Zero Gate Voltage Drain Current $V_{DS} = 24 \text{V}, V_{GS} = 0 \text{V}$ Q1 Gate to Source Leakage Current $V_{CS} = 20 \text{V}, V_{CS} = 0 \text{V}$ Q1	Cteristics Drain to Source Breakdown Voltage $I_D = 250 \mu A$, $V_{GS} = 0 V$ Q1 30 30 30 Breakdown Voltage Temperature Coefficient $I_D = 250 \mu A$, referenced to 25 °C Q1 ID = 1 mA, referenced to 25 °C Q2 ID = 1 mA, refe	Cteristics Drain to Source Breakdown Voltage $I_D = 250 \mu A, V_{GS} = 0 V$ $I_D = 1 \text{mA}, V_{GS} = 0 V$ $Q2 30$ Breakdown Voltage Temperature Coefficient $I_D = 250 \mu A, \text{referenced to } 25 ^{\circ}\text{C}$ $I_D = 1 \text{mA}, \text{referenced to } 25 ^{\circ}\text{C}$ $Q2 14$ Zero Gate Voltage Drain Current $V_{DS} = 24 V, V_{GS} = 0 V$ $Q1 Q2 Q2$ Gate to Source Leakage Current $V_{CS} = 20 V, V_{CS} = 0 V$	Cteristics Drain to Source Breakdown Voltage $I_D = 250 \mu A, V_{GS} = 0 V$ $I_D = 1 \text{mA}, V_{GS} = 0 V$ $Q1 30 Q2 30$ Breakdown Voltage Temperature Coefficient $I_D = 250 \mu A, \text{referenced to } 25 ^{\circ}\text{C}$ $Q1 15 Q2 14$ Zero Gate Voltage Drain Current $V_{DS} = 24 V, V_{GS} = 0 V$ $Q1 15 Q2 14$ Gate to Source Leakage Current $V_{OS} = 20 V, V_{OS} = 0 V$ $Q1 100 Q1 Q1$

On Characteristics

V _{GS(th)}	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}, I_D = 250 \mu A$ $V_{GS} = V_{DS}, I_D = 1 mA$	Q1 Q2	1 1	1.8 1.5	3	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate to Source Threshold Voltage Temperature Coefficient	I_D = 250 μA, referenced to 25 °C I_D = 1 mA, referenced to 25 °C	Q1 Q2		-6 -4		mV/°C
		$V_{GS} = 10 \text{ V}, \ I_D = 12 \text{ A}$ $V_{GS} = 4.5 \text{ V}, \ I_D = 10 \text{ A}$ $V_{GS} = 10 \text{ V}, \ I_D = 12 \text{ A}, \ T_J = 125 ^{\circ}\text{C}$	Q1		6.0 8.5 8.3	7.5 12 12	
r _{DS(on)}	Drain to Source On Resistance	$V_{GS} = 10 \text{ V}, \ I_D = 20 \text{ A}$ $V_{GS} = 4.5 \text{ V}, \ I_D = 18 \text{ A}$ $V_{GS} = 10 \text{ V}, \ I_D = 20 \text{ A}, \ T_J = 125 ^{\circ}\text{C}$	Q2		1.9 2.2 2.1	2.4 2.9 3.4	mΩ
9 _{FS}	Forward Transconductance	$V_{DS} = 5 \text{ V}, I_{D} = 12 \text{ A}$ $V_{DS} = 5 \text{ V}, I_{D} = 20 \text{ A}$	Q1 Q2		63 160		S

Dynamic Characteristics

C _{iss}	Input Capacitance	Q1: V _{DS} = 15 V, V _{GS} = 0 V, f = 1 MHZ	Q1 Q2	1315 7240	1750 9630	pF
C _{oss}	Output Capacitance	Q2:	Q1 Q2	445 2690	600 3580	pF
C _{rss}	Reverse Transfer Capacitance	$V_{DS} = 15 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHZ}$	Q1 Q2	45 185	70 280	pF
R _g	Gate Resistance		Q1 Q2	0.9 0.8		Ω

Switching Characteristics

t _{d(on)}	Turn-On Delay Time		Q1 Q2	8.6 21	18 34	ns
t _r	Rise Time	Q1: $V_{DD} = 15 \text{ V}, I_{D} = 12 \text{ A}, R_{GEN} = 6 \Omega$ Q2: $V_{DD} = 15 \text{ V}, I_{D} = 20 \text{ A}, R_{GEN} = 6 \Omega$	$E_N = 6 \Omega$ Q1 Q2	2.5 9.2	10 18	ns
t _{d(off)}	Turn-Off Delay Time		Q1 Q2	20 58	32 93	ns
t _f	Fall Time		Q1 Q2	2.3 6.8	10 14	ns
Qg	Total Gate Charge	V _{GS} = 0 V to 10 V Q1	Q1 Q2	20 105	28 147	nC
Q _g	Total Gate Charge	$V_{GS} = 0 \text{ V to } 4.5 \text{ V}$ $I_{D} = 15 \text{ V},$ $I_{D} = 12 \text{ A}$	15 V, Q1 2 A Q2	9.3 48	13 67	nC
Q _{gs}	Gate to Source Gate Charge	Q2 V _{DD} =	Q1 Q2	4.3 19		nC
Q _{gd}	Gate to Drain "Miller" Charge	I _D = 20	~ 4	2.2 11		nC

Electrical Characteristics $T_J = 25$ °C unless otherwise noted

Symbol	Parameter	Test Conditions	Туре	Min	Тур	Max	Units
Drain-Source Diode Characteristics							
V_{SD}	Source to Drain Diode Forward Voltage	$V_{GS} = 0 \text{ V}, I_S = 12 \text{ A}$ (Note 2) $V_{GS} = 0 \text{ V}, I_S = 20 \text{ A}$ (Note 2)			0.8 0.7	1.2 1.2	V
t _{rr}	Reverse Recovery Time	Q1 I _F = 12 A, di/dt = 100 A/μs	Q1 Q2		27 53	43 85	ns
Q _{rr}	Reverse Recovery Charge	Q2 $I_F = 20 \text{ A, di/dt} = 300 \text{ A/}\mu\text{s}$	Q1 Q2		10 100	18 160	nC

Notes:1: $R_{\theta JA}$ is determined with the device mounted on a 1 in² pad 2 oz copper pad on a 1.5 x 1.5 in. board of FR-4 material. $R_{\theta JC}$ is guaranteed by design while $R_{\theta CA}$ is determined by the user's board design.



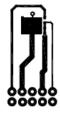
a. 57 °C/W when mounted on a 1 in² pad of 2 oz copper



b. 50 °C/W when mounted on a 1 in² pad of 2 oz copper



c. 125 °C/W when mounted on a minimum pad of 2 oz copper



d. 120 °C/W when mounted on a minimum pad of 2 oz copper

- 2: Pulse Test: Pulse Width < 300 μ s, Duty cycle < 2.0%.
- 3: As an N-ch device, the negative Vgs rating is for low duty cycle pulse ocurrence only. No continuous rating is implied.

Typical Characteristics (Q1 N-Channel)T_J = 25°C unless otherwise noted

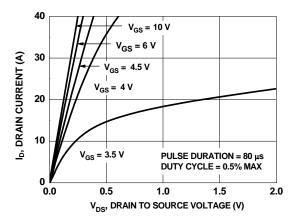


Figure 1. On Region Characteristics

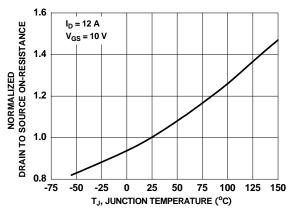


Figure 3. Normalized On Resistance vs Junction Temperature

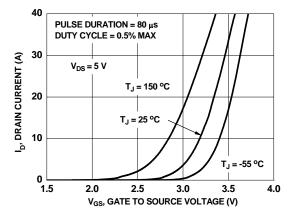


Figure 5. Transfer Characteristics

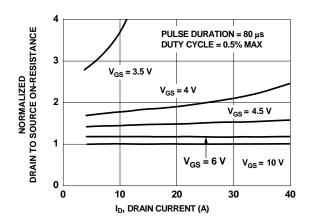


Figure 2. Normalized On-Resistance vs Drain Current and Gate Voltage

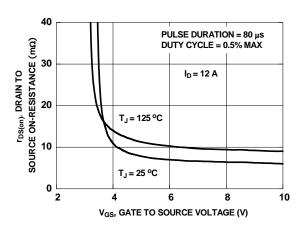


Figure 4. On-Resistance vs Gate to Source Voltage

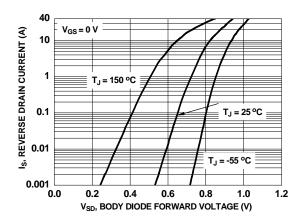


Figure 6. Source to Drain Diode Forward Voltage vs Source Current

Typical Characteristics (Q1 N-Channel)T_J = 25°C unless otherwise noted

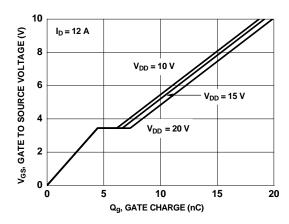


Figure 7. Gate Charge Characteristics

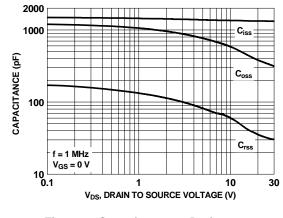


Figure 8. Capacitance vs Drain to Source Voltage

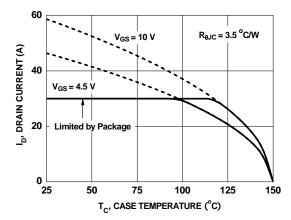


Figure 9. Maximum Continuous Drain Current vs Case Temperature

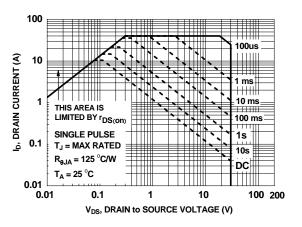


Figure 10. Forward Bias Safe Operating Area

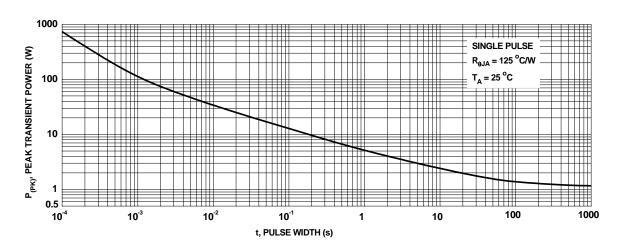


Figure 11. Single Pulse Maximum Power Dissipation

Typical Characteristics (Q1 N-Channel) $T_J = 25^{\circ}C$ unless otherwise noted

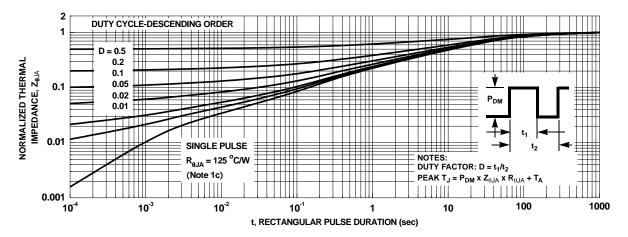


Figure 12. Junction-to-Ambient Transient Thermal Response Curve

Typical Characteristics (Q2 SyncFET)

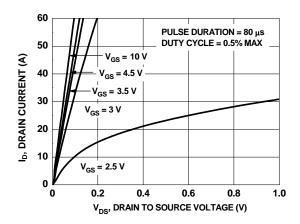


Figure 13. On-Region Characteristics

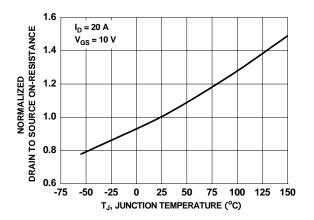


Figure 15. Normalized On-Resistance vs Junction Temperature

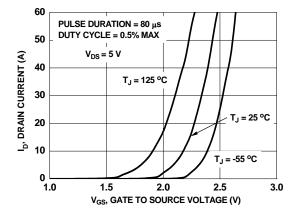


Figure 17. Transfer Characteristics

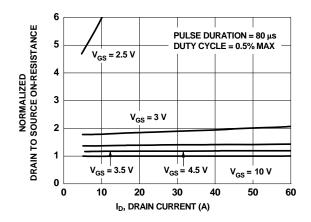


Figure 14. Normalized on-Resistance vs Drain Current and Gate Voltage

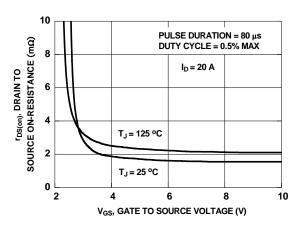


Figure 16. On-Resistance vs Gate to Source Voltage

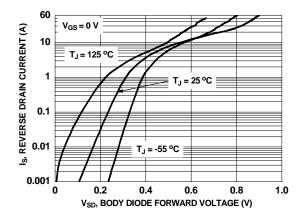


Figure 18. Source to Drain Diode Forward Voltage vs Source Current

Typical Characteristics (Q2 SyncFET)

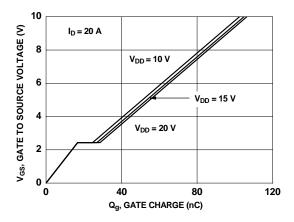


Figure 19. Gate Charge Characteristics

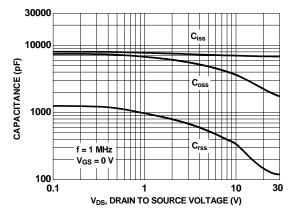


Figure 20. Capacitance vs Drain to Source Voltage

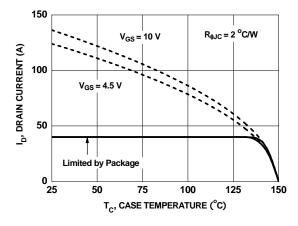


Figure 21. Maximum Continuous Drain Current vs Case Temperature

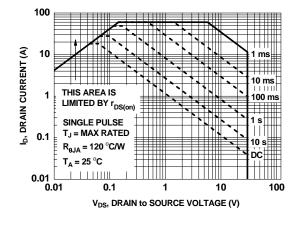


Figure 22. Forward Bias Safe Operating Area

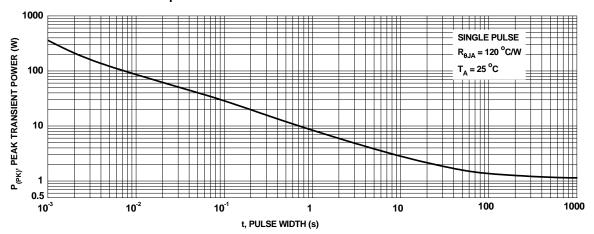


Figure 23. Single Pulse Maximum Power Dissipation

Typical Characteristics (Q2 SyncFET)

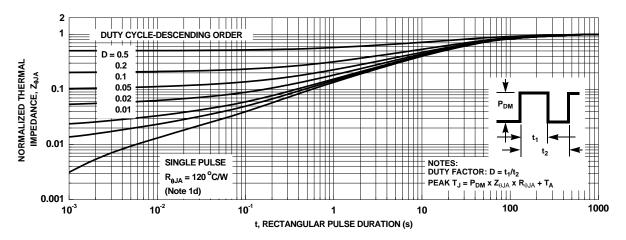


Figure 24. Junction-to-Ambient Transient Thermal Response Curve

Typical Characteristics (continued)

SyncFETTM Schottky Body Diode Characteristics

Fairchild's SyncFETTM process embeds a Schottky diode in parallel with PowerTrench[®] MOSFET. This diode exhibits similar characteristics to a discrete external Schottky diode in parallel with a MOSFET. Figure 25 shows the reverse recovery characteristic of the FDMS7700S.

Schottky barrier diodes exhibit significant leakage at high temperature and high reverse voltage. This will increase the power in the device.

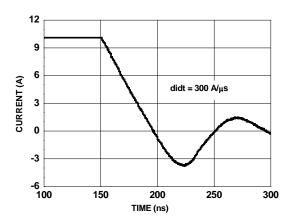


Figure 25. FDMS7700S SyncFETTM Body Diode Reverse Recovery Characteristic

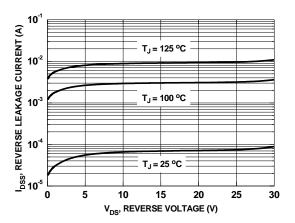
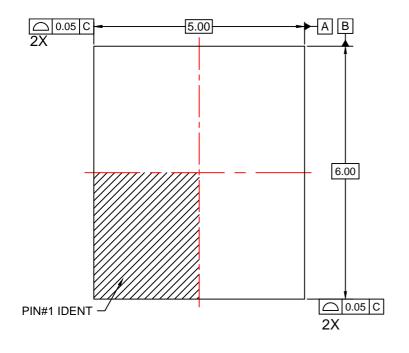
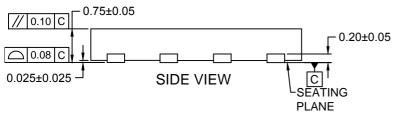
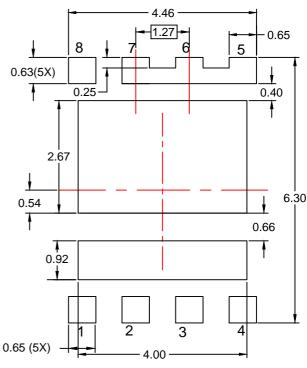


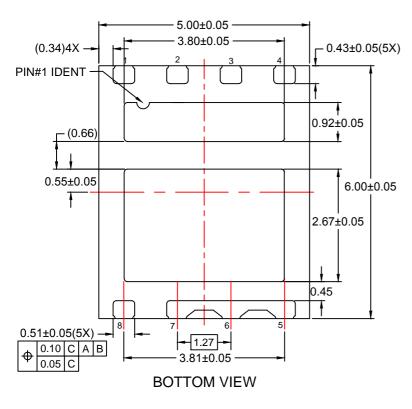
Figure 26. SyncFETTM Body Diode Reverse Leakage vs. Drain-Source Voltage





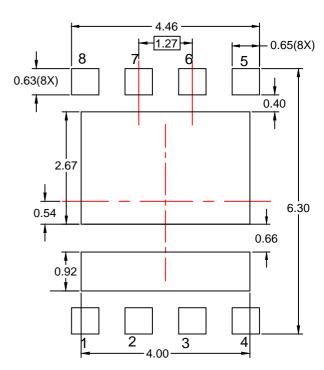


RECOMMENDED LAND PATTERN (OPTION 1 - FUSED LEADS 5,6,7)



NOTES:

- A. PACKAGE DOES NOT FULLY CONFORM TO JEDEC STANDARD.
- B. DIMENSIONS ARE IN MILLIMETERS.
- C. DIMENSIONS AND TOLERANCES PER ASME Y14.5M, 2009.
- D. LAND PATTERN RECOMMENDATION IS EXISTING INDUSTRY LAND PATTERN.
- E. DRAWING FILENAME: MKT-MLP08Prev2.



RECOMMENDED LAND PATTERN (OPTION 2 - ISOLATED LEADS)



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